

Enhancement Mode N-Channel Power MOSFET

PDFN5X6/NMOS/60V/ \pm 20V/1.6V/70A/6.2m Ω

Rev_{0.5}





60V, 6.2 mΩ, 70A, N-Channel MOSFET

1.Features

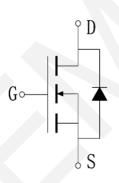
- ♦ 40V MOSFET technology
- ◆ Low on-state resistance
- Fast switching
- ♦ Vgs±20V
- ♦ 100% RG Tested
- ◆ 100% UIS Tested

| 2.A | pp | lic | atio | ns |
|-----|----|------|------|------|
| 4./ | PP | ,,,, | atio | ,,,, |

- Power Switching Application
- ◆ Load Switching



| V _{DS} | R _{DS(on)} Typ. | I _D Max. | |
|-----------------|--------------------------|---------------------|--|
| 60V | 6.2mΩ @ 10V | 704 | |
| | 8.7mΩ @ 4.5V | 70A | |



Schematic Diagram

3. Package Marking and Ordering Information

| Part no. | Marking | Package | PCS/Reel | PCS/CTN. |
|-----------|---------|---------|----------|----------|
| WP6070APA | 6070A | PDFN5X6 | 5,000 | 50,000 |

4.Absolute Max Ratings at Ta=25°C (Note1)

| Parameter | Symbol | Maximum | Units |
|---------------------------------|-------------------|-------------|-------|
| Drain to Source Voltage | $V_{	extsf{DSS}}$ | 60 | V |
| Gate to Source Voltage | V_{GSS} | ±20 | V |
| Drain Current (DC) | I _D | 70 | А |
| Drain Current (Pulse), PW≤300μs | I _{DP} | 280 | А |
| Total Dissipation | P_{D} | 89 | W |
| Avalanche Energy, Single Pulsed | E _{AS} | 110.25 | mJ |
| Junction Temperature | T _j | 150 | °C |
| Storage Temperature | T_{stg} | -55 to +150 | °C |

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



5. Thermal Resistance Ratings

| Parameter | Symbol | Value | Unit |
|------------------|----------------|-------|------|
| Junction to case | $R_{	heta JC}$ | 1.4 | °C/W |

Note 2: When mounted on 1 inch square copper board $t \le 10$ sec The value in any given application depends on the user's specific board design.

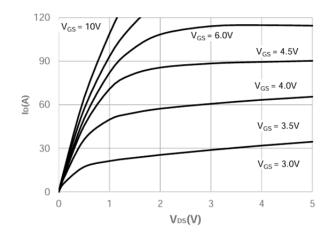
6.Electrical Characteristics at Ta=25°C (Note 3)

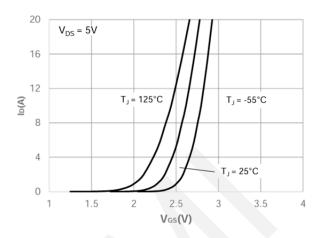
| Parameter | Symbol | Test Conditions | Min. | Тур. | Max. | Units |
|-----------------------------------|----------------------|---|------|------|------|-------|
| Drain to Source Breakdown Voltage | V _{(BR)DSS} | $I_D = 250 \mu A, V_{GS} = 0 V$ | 40 | - | - | V |
| Zero-Gate Voltage Drain Current | I _{DSS} | $V_{DS} = 60V, V_{GS} = 0V$ | - | 1 | 1 | μA |
| Gate to Source Leakage Current | I _{GSS1} | $V_{GS} = \pm 20V, V_{SS} = 0V$ | - | - | ±100 | nA |
| Gate Threshold Voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}$, $I_{DS}=250\mu A$ | 1.3 | 1.6 | 2.0 | V |
| Static Drain to Source On-State | Б | $I_D = 20A, V_{GS} = 10V$ | 1 | 6.2 | 8.5 | mΩ |
| Resistance | R _{DS(on)} | $I_D = 10A, V_{GS} = 4.5V$ | - | 8.7 | 13 | mΩ |
| Input Capacitance | C _{iss} | V _{GS} =0V, | - | 1193 | - | pF |
| Output Capacitance | C _{oss} | V _{DS} =30V, | - | 525 | - | pF |
| Reverse Transfer Capacitance | C _{rss} | Frequency=1.0MHz | - | 36 | - | pF |
| Turn-ON Delay Time | t _{d(on)} | V _{DD} = 30V, | - | 7.6 | - | ns |
| Rise Time | t _r | $I_D = 20A,$ | - | 20 | - | ns |
| Turn-OFF Delay Time | t _{d(off)} | $V_{GS} = 10V$, | - | 22 | - | ns |
| Fall Time | t _f | $R_{GEN} = 3\Omega$ | - | 6.6 | - | ns |
| | Q_g | $V_{DS} = 30V$, $V_{GS} = 0$ to 10V, $I_{D} = 20A$ | - | 22 | - | nC |
| Total Gate Charge | Q _{gs} | | - | 3.9 | - | nC |
| | Q_{gd} | | - | 5.1 | - | nC |
| Diode Forward Voltage | V_{FSD} | I _S = 20A, V _{GS} = 0 | 0.5 | _ | 1.2 | V |

Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

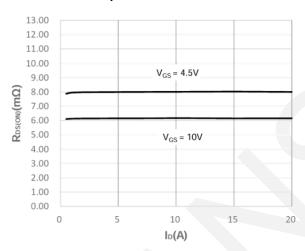


7. Typical electrical and thermal characteristics

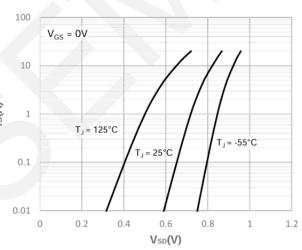




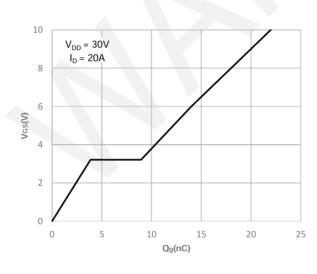
Output Characteristics



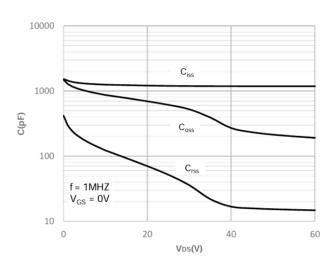
Typical Transfer Characteristics



On-resistance vs. Drain Current



Body Diode Characteristics

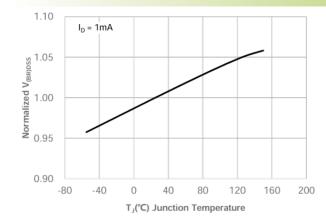


Gate Charge Characteristics

Capacitance Characteristics







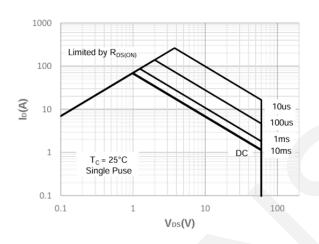
2.2 2 Pulse Width≤300µs Duty Cycle≤0.5% V_{GS} = 10V 1.8 Normalized R_{DS(ON)} 1.6 1.4 1.2 $V_{GS} = 4.5V$ 0.8 0.6 0.4 -80 -40 0 40 80 200 120 160 T_J(°C) Junction Temperature

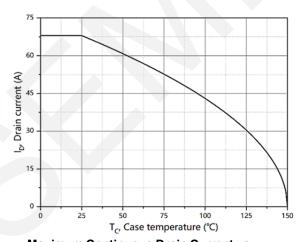
Normalized Breakdown Voltage vs.

Junction Temperature

Normalized on Resistance vs.

Junction Temperature





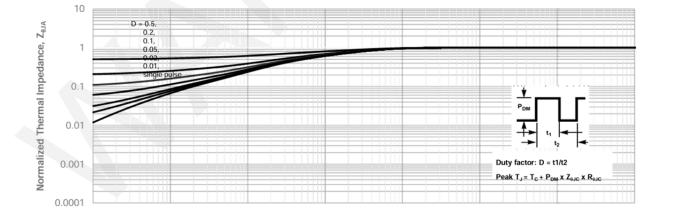
Maximum Safe Operating Area

Maximum Continuous Drain Current vs.

Case Temperature

1.E-1

1.E+0



1.E-3

t, Rectangular Pulse Width (s)

1.E-2

Thermal Impedance

Normalized Maximum Transient

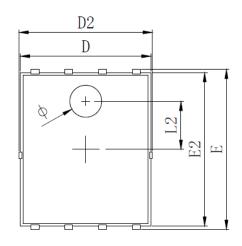
1.E-4

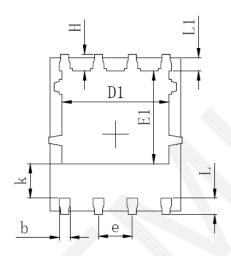
1.E-5

1.E+1



8.Package Dimensions





| SYMBOL | MILLIMETER | | | |
|--------|------------|-------------|--------|--|
| SYMDUL | MIN | Тур. | MAX | |
| A | 0. 900 | 1. 000 | 1. 100 | |
| A1 | | 0. 254 REF. | | |
| A2 | | 0~0. 05 | | |
| D | 4. 824 | 4. 900 | 4. 976 | |
| D1 | 3. 910 | 4. 010 | 4. 110 | |
| D2 | 4. 924 | 5. 000 | 5. 076 | |
| E | 5. 924 | 6. 000 | 6. 076 | |
| E1 | 3. 375 | 3. 475 | 3. 575 | |
| E2 | 5. 674 | 5. 750 | 5. 826 | |
| b | 0. 350 | 0. 400 | 0. 450 | |
| е | | 1.270 TYP. | | |
| L | 0. 534 | 0. 610 | 0. 686 | |
| L1 | 0. 424 | 0. 500 | 0. 576 | |
| L2 | 1.800 REF. | | | |
| k | 1. 190 | 1. 290 | 1. 390 | |
| Н | 0. 549 | 0. 625 | 0. 701 | |
| θ | 8° | 10° | 12° | |
| ф | 1. 100 | 1. 200 | 1. 300 | |
| d | | | 0.100 | |



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